

Future of Power Efficient Processing



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Power Efficient Electronics are Critical to Many DoD Missions



**Soldiers carry packs in 70-120 lbs range
Frequently 10-20 lbs are batteries!**



**Power is frequently scarce and expensive:
UAVs, remote sensor networks, space, etc.**



DSRC Summer 2006
Low Power Workshop

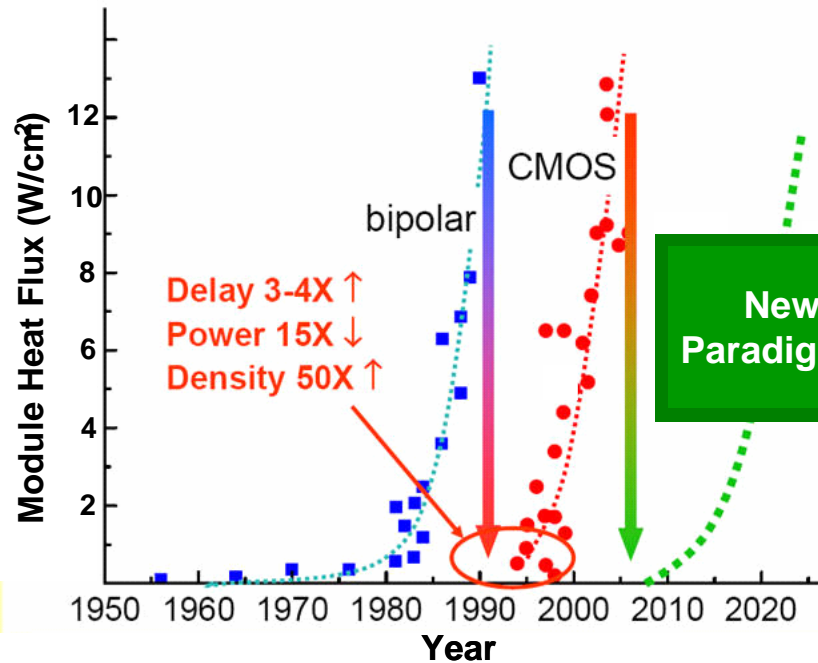
**Getting rid of dissipated heat
is often a major problem by itself!**



Heat pipes



Electronics History: Power Efficiency Perspective



$$\text{Power} = \text{Dynamic} + \text{Static}$$
$$= 0.5CV_{dd}^2f + I_{leak}V_{dd}$$

Ultimate Goals:

Decades power reduction
No performance penalty

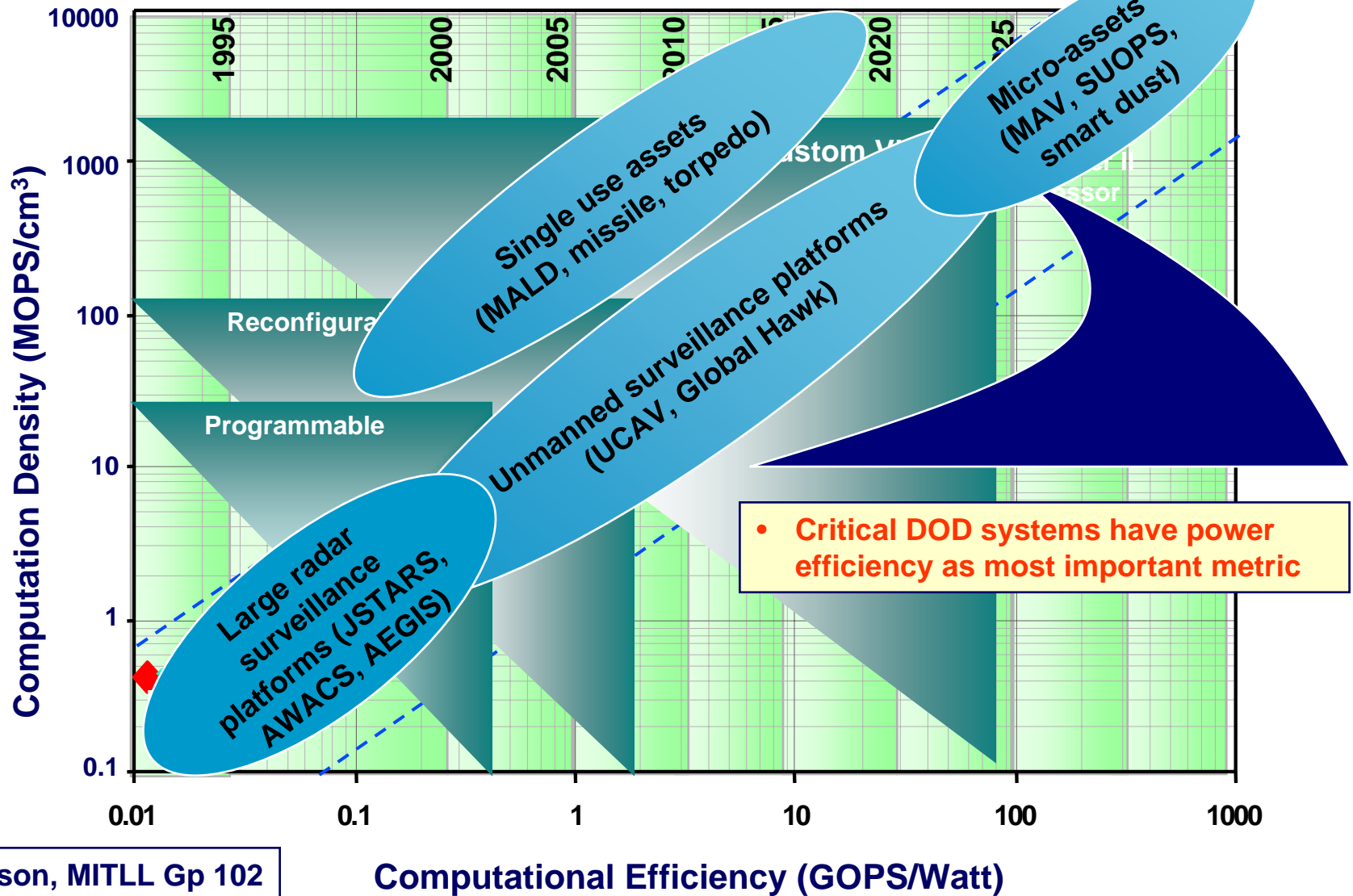
- Each technology ultimately reaches integration density limited by power dissipation
- Quantum jump then occurs to new technology with lower power

Time for the next paradigm change ?



Embedded Computing for DoD

Power Efficiency (Ops/Watt) is Key



J. Anderson, MITLL Gp 102
HPEC Conference '04-'05



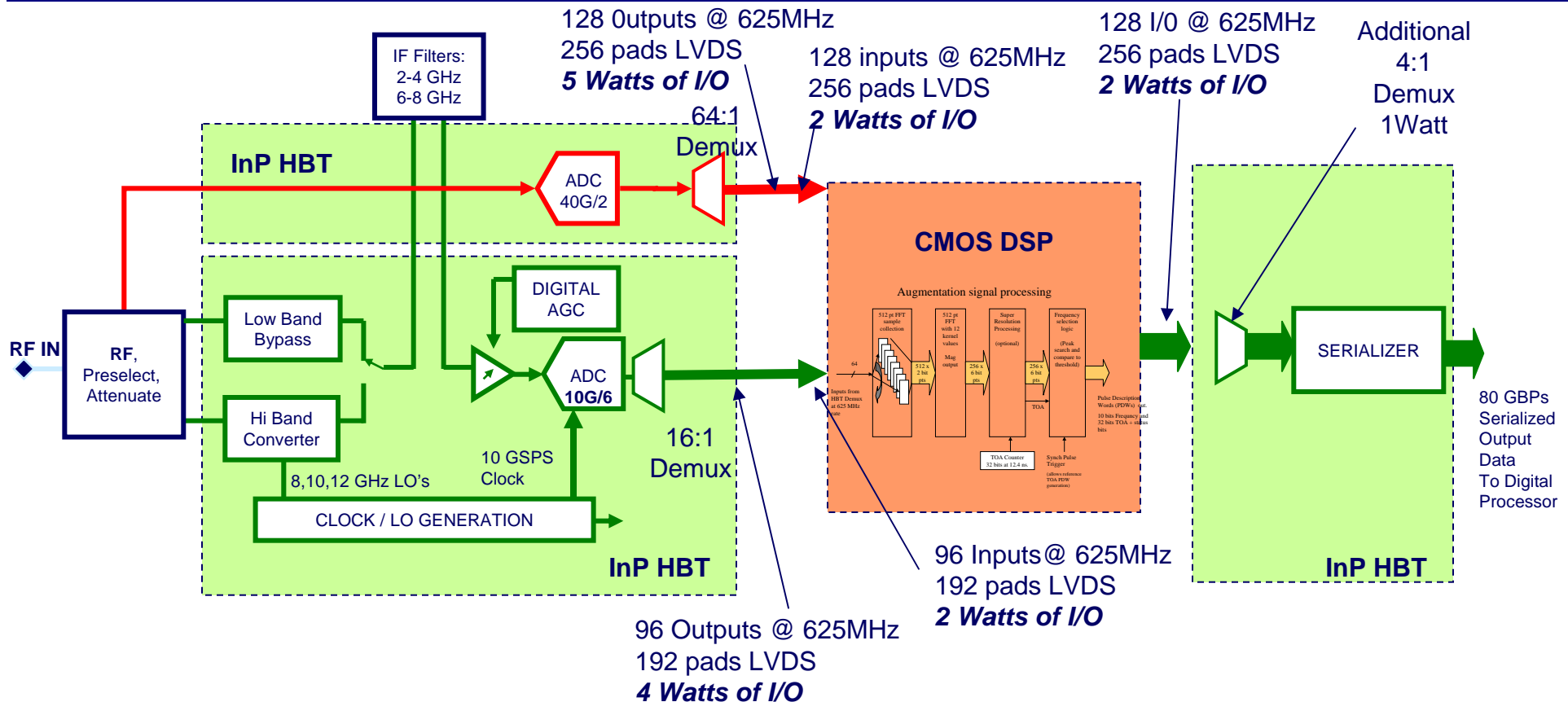
Some Paths Forward: Power Efficiency



- **I) Densely integrated RF technology**
 - RF SOC vs MCM implementation
 - ‘TEAM’
- **II) Novel Architecture/Design**
 - Power management
 - Sub-threshold , Parallelism, 3D
 - ‘ESE’, ‘3D-IC’
- **III) Ultra-low power CMOS**
 - Tunable threshold
 - Steeper sub-threshold slope (< 62 mV/dec)
 - ‘STEEP’ BAA coming out
- **IV) Beyond Silicon**
 - Carbon electronics
 - Graphene, Nanotubes
 - **Workshop in early April**



Power Benefits of Integration: RF-SOC vs. MCM

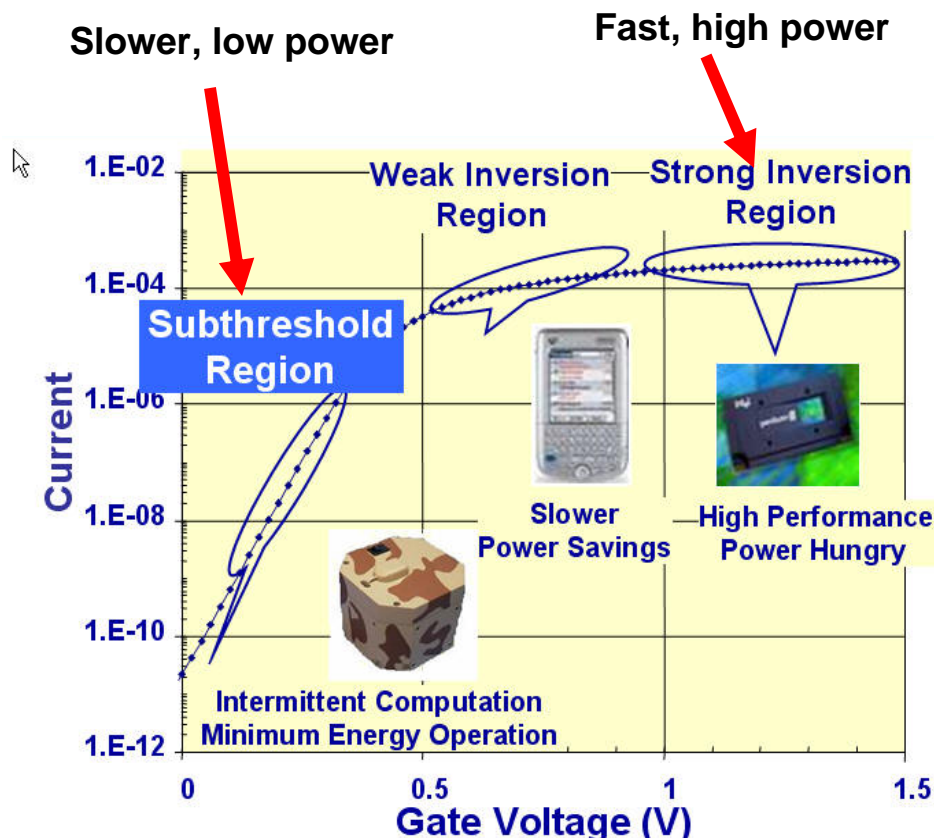


All four ICs can be implemented in a single SiGe IC

... 16 Watts of additional power due to intra-chip I/O in multi-chip approach over a monolithic implementation



Sub-threshold Digital Design: Energy Starved Electronics (ESE) Program

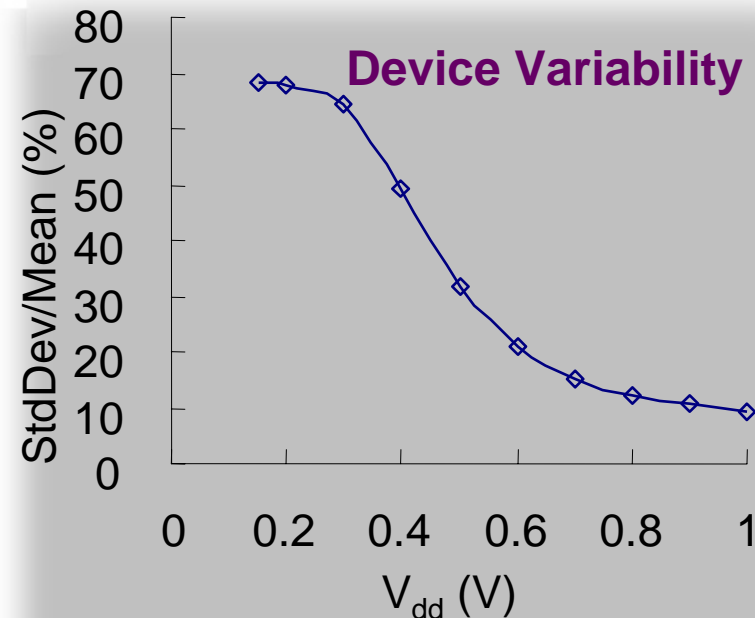
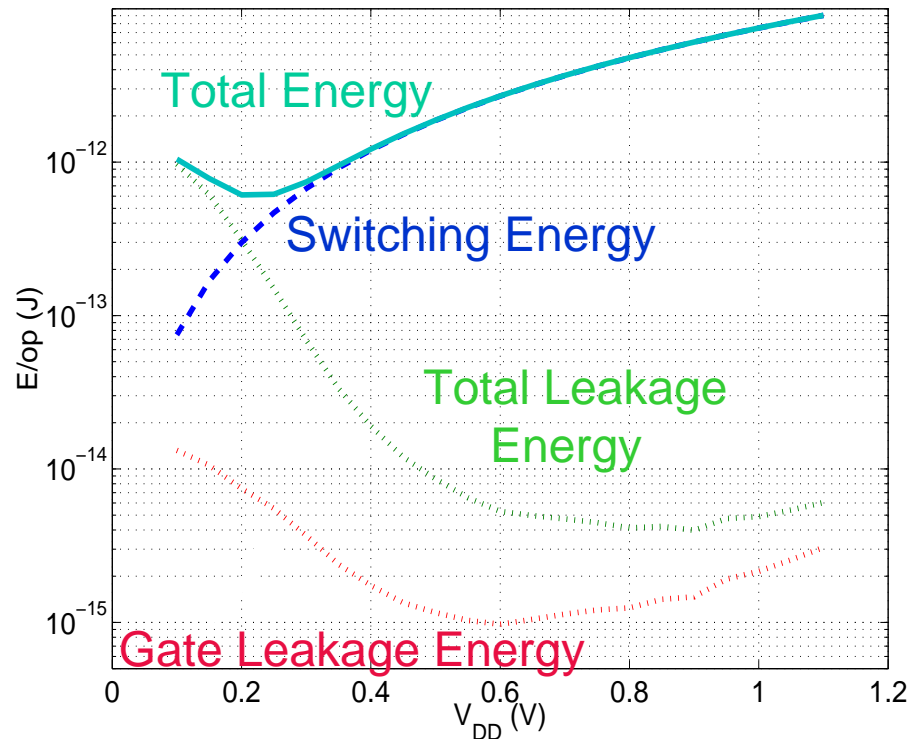


- Goal: Enable ultra-low power digital circuits operating in the *sub-threshold regime* while maintaining adequate performance. Energy consumption savings > 10X.
- Technical Challenges:
 - Develop standard cells operating at $V_{dd} < 300$ mV; esp. SRAM
 - Achieving adequate performance (through parallelism)
 - Addressing high sensitivity to variations (via ECC)
- Design Only Approach:
 - No device technology changes
 - Exploits massive investment by industry for DoD benefit

PI: Prof. Anantha Chandrakasan, MIT
Fab: TI, Dr. Dennis Buss, 65-nm CMOS



Minimum Energy Point: Switching vs. Leakage



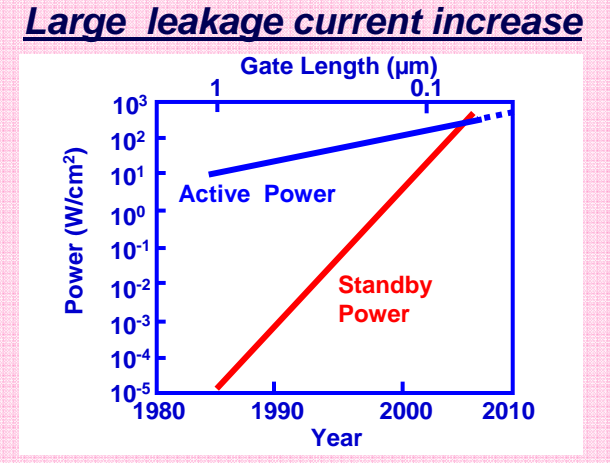
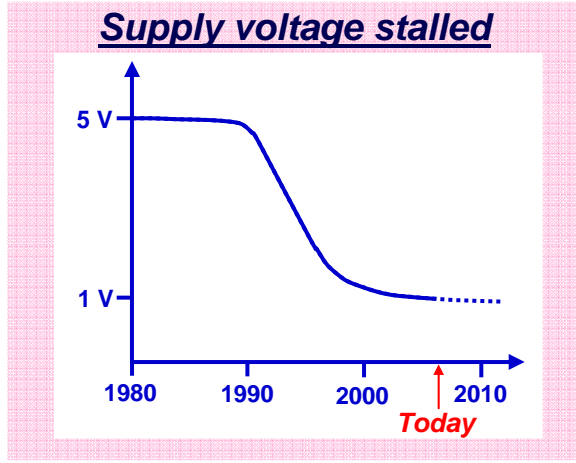
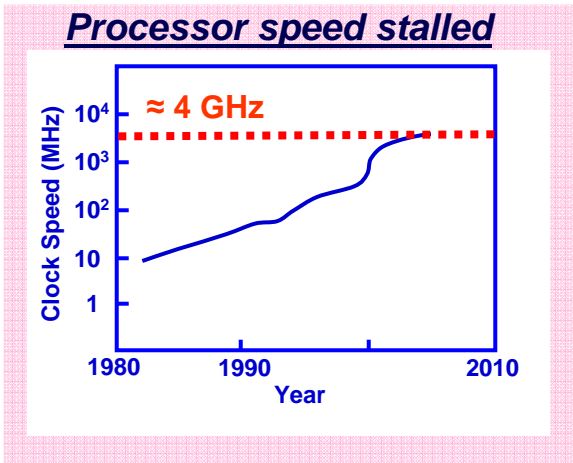
- **Minimum energy point \approx 200 mV (sub-threshold regime)**
 - Must be compensated for (e.g., parallelism and threshold control)
 - Optimum voltage V_{dd} varies with circuit activity
- Leakage energy increases at extremely low voltages (long delay times)
- Increased variability requires wider margins, reduced performance



Steep-subthreshold-slope Transistors for Electronics with Extremely-low Power (STEEP)

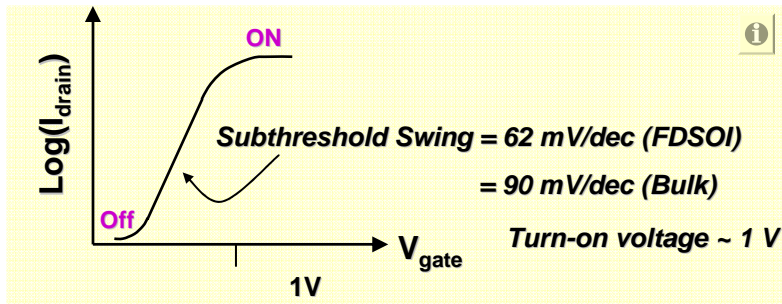


Problem: Device Scaling alone will no longer meet DoD needs!



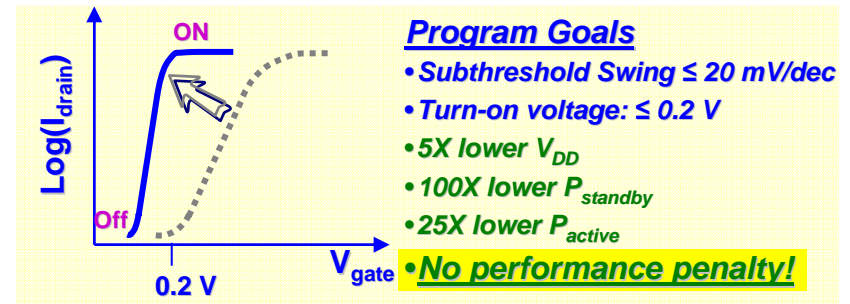
Proposed Solution: Steep-subthreshold-slope Transistors

Today



Theoretical minimum of the subthreshold swing of MOSFET is $\ln 10(kT/q)$ or 60 mV/dec

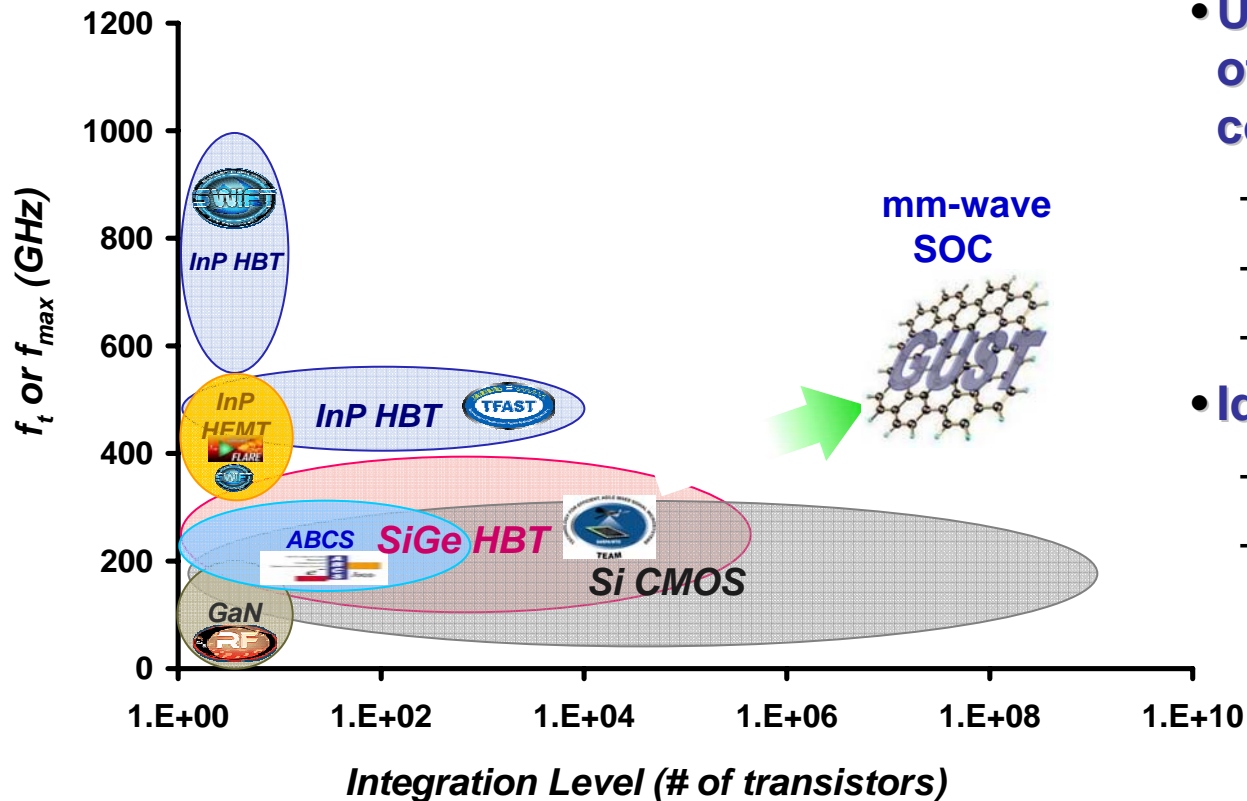
STEEP Vision



Develop ideal transistor switch for ultra-low power electronics



Carbon Electronics: High Performance & Integration for RF-SOC's



- Ultimate performance limits of mm-wave devices (radar, comms, etc):
 - Higher speeds
 - Improved power efficiency
 - Lower “SWAP”
- Ideal mm-wave device
 - Key parameters
 - Integration path with Si

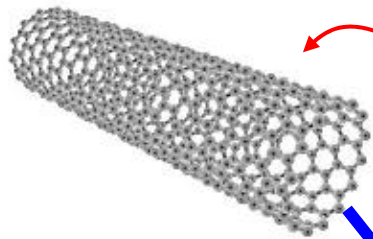
New Opportunity: Carbon-based mm-wave SOC's



New Approach For Ideal mm-wave Material: Planar Carbon (Graphene)



Carbon Nanotube



Challenges:

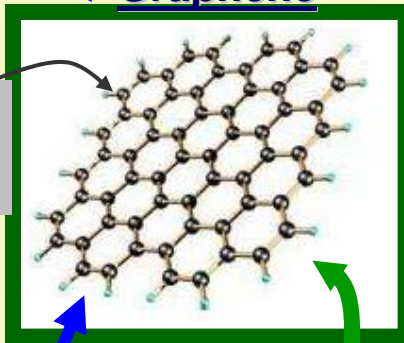
**Placement
&
Uniformity**

unroll

Graphene

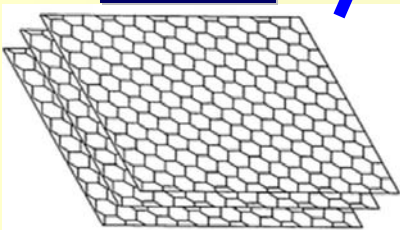
Planar system

sp^2 hexagonal
 $a=0.25\text{nm}$, $c=0.67\text{nm}$
2D physics



"scrape"

Graphite



**Planar form has most of
the desirable properties
of nanotubes**

Graphene Properties:

- High mobilities for both electron & hole ($> 10X$ silicon)
 - $\mu \geq 15,000 \text{ cm}^2/\text{Vs}$, $m^* = 0.06m_0$
 - mm-wave & low power potential
 - High current density
- Ideal electrostatics ("monolayer-on-insulator")
 - Sub-nm thickness
 - $< \text{Debye screening length}$
 - Enables aggressive scaling
- Planar processing can be used
 - Standard paradigm
 - Straightforward integration with CMOS

Semimetal band structure

- $I_{\text{on}}/I_{\text{off}} \sim 30$, useful for RF devices

Graphene is very promising material for mm-wave RF-SOC technology



A Possible Path Forward

